

Search Notes



Application/Control No.

10/534,134

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

JEONG ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
392	386		
	387		
	388		
	389		
118	726		
427	192		
	193		
	113		
427	401		
	216	4/27/06	JP
updated as above		10/10/06	Y

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Exam that searched	4/27/06	JP